



# **Single Event Transients (SET) in linear devices - NASA/GSFC studies**

**Christian Poivey, Steve Buchner, Jim  
Howard, Ken LaBel, Christina Seidleck,  
Hak Kim, Jim Forney, Chris Palor**

# Background

- SET studies started in 1999 with the objective to define a low cost conservative test methodology.
  - study on 139 voltage comparators from two vendors (NSC, Intersil) and LM124 operational amplifier from NSC under many operational conditions.
  - The results showed that the worst case test condition is specific for each device (2001 NSREC paper).
- More data was collected to understand the effect of bias conditions and support Vanderbilt modeling effort.
- Lessons learned during testing have been used to define testing guidelines.
- Laser studies were performed.

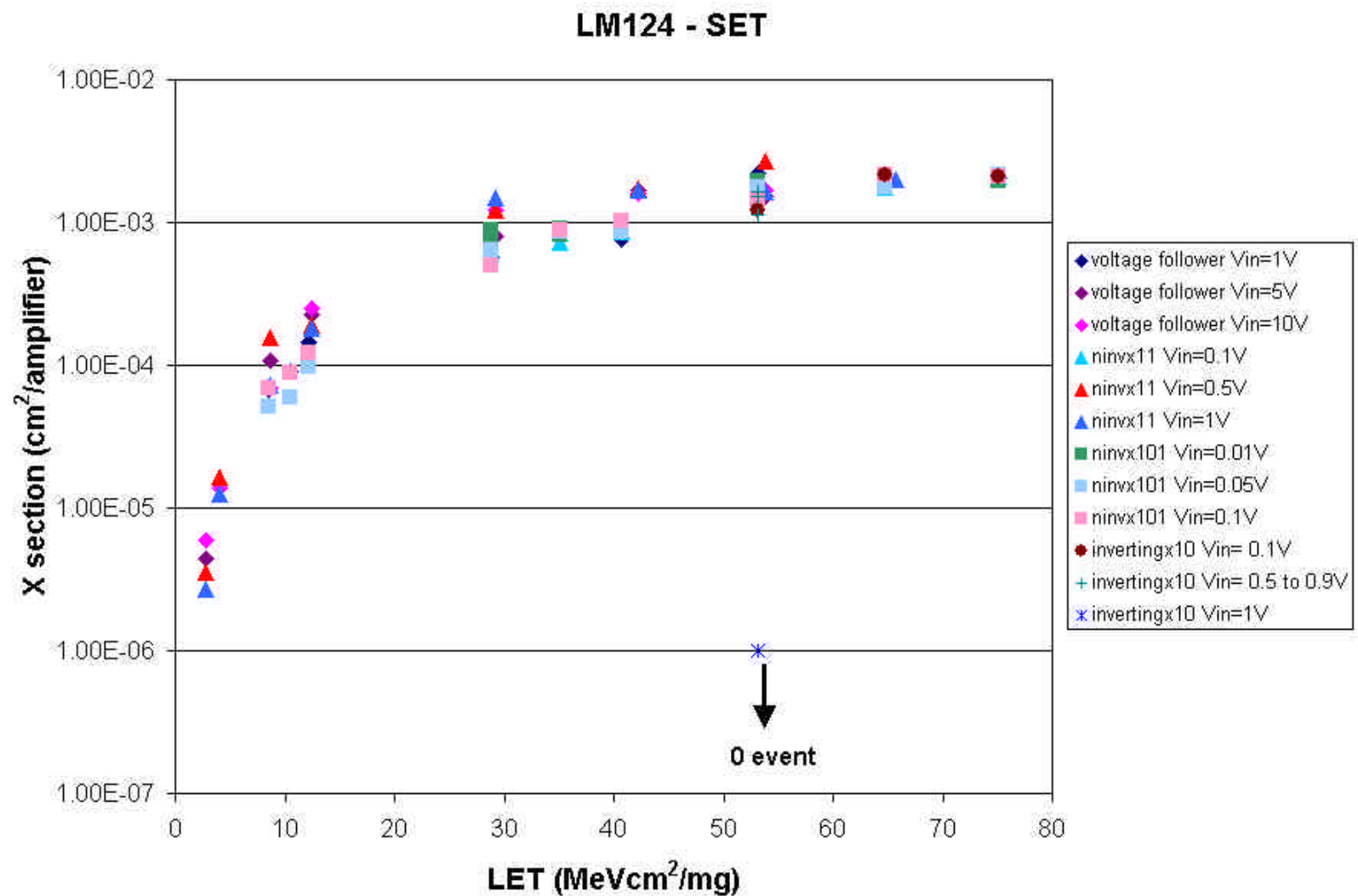
# Objectives of NASA-GSFC SET studies

- Collect SET data on common linear devices used in NASA missions.
- Issue of NASA guidelines for SET testing of linear devices.
- Collect broad beam and laser test data in support of Vanderbilt modeling effort.
- Evaluate the laser tool for Radiation Hardness Assurance of linear devices

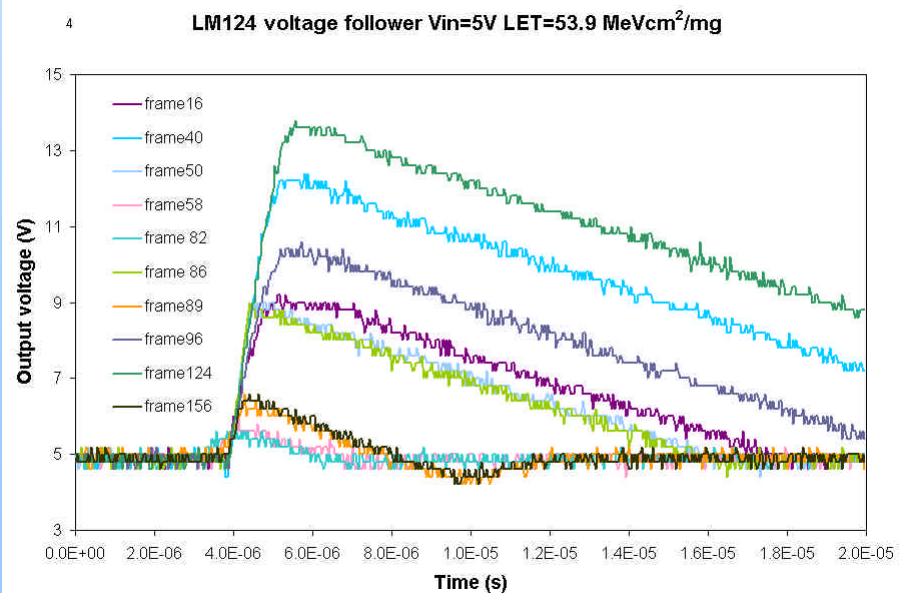
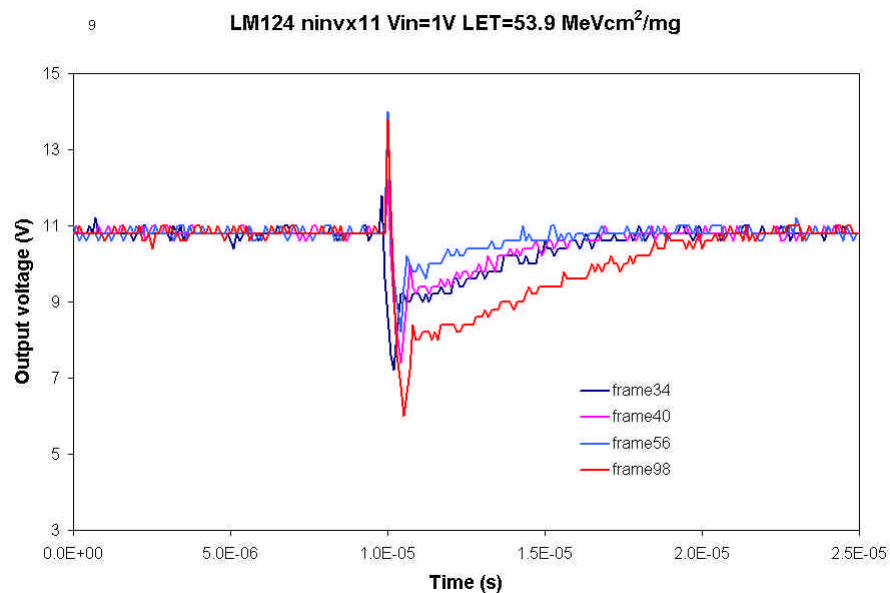
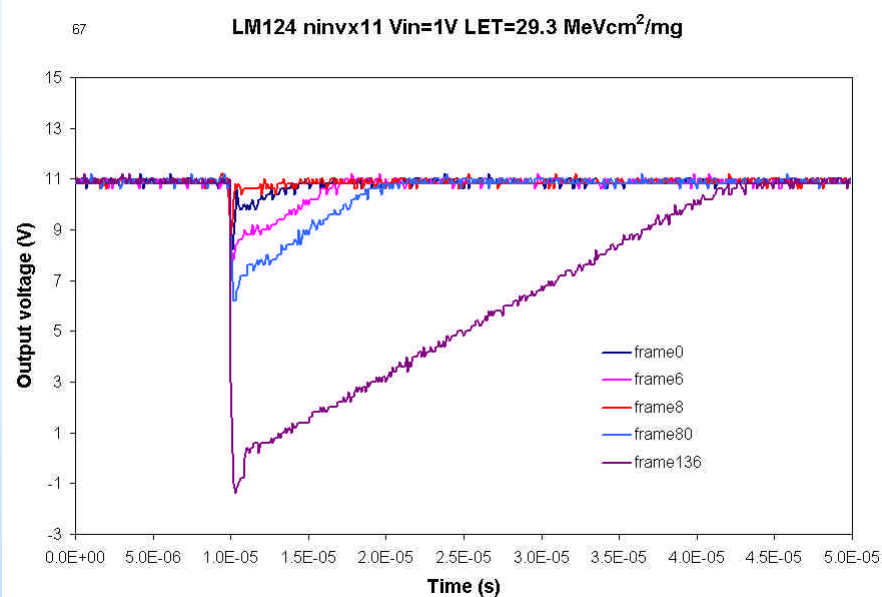
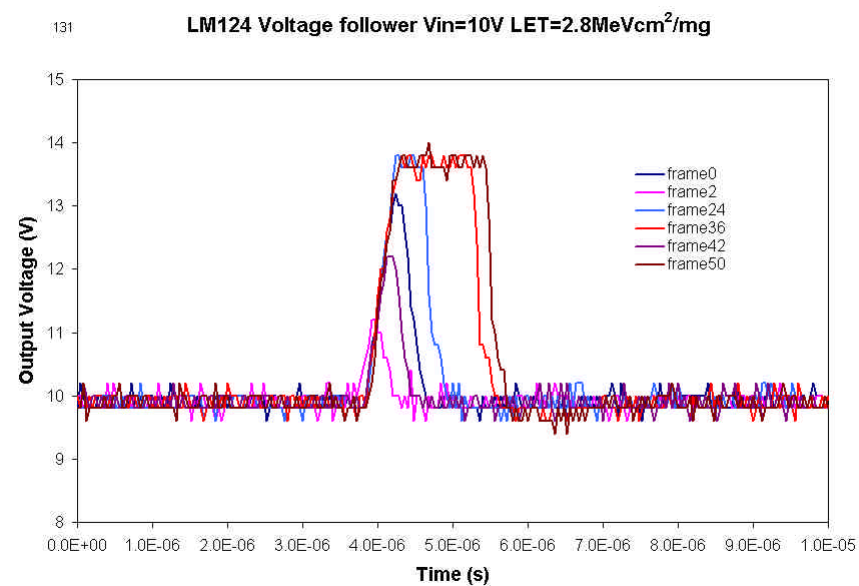
# 2002/2003 activities

- Broad beam testing
  - LM124, LMC6484, LT1128
  - Project testing: OP293, MAX494, SG1525,...
  - OP27, LM6144 (NAVSEA CRANE)
- Laser testing at NRL
  - LM124, LMC6484, OP27
    - LM124 paper submitted to RADECS
  - LM6144, OP293, SG1525,...
- Issue of SET test guidelines

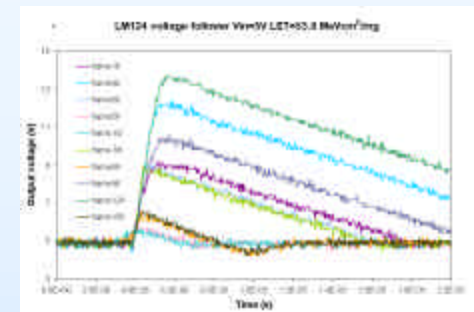
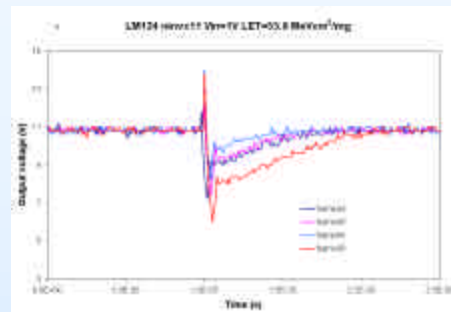
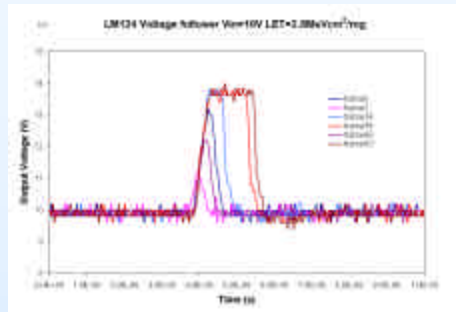
# Results – LM124



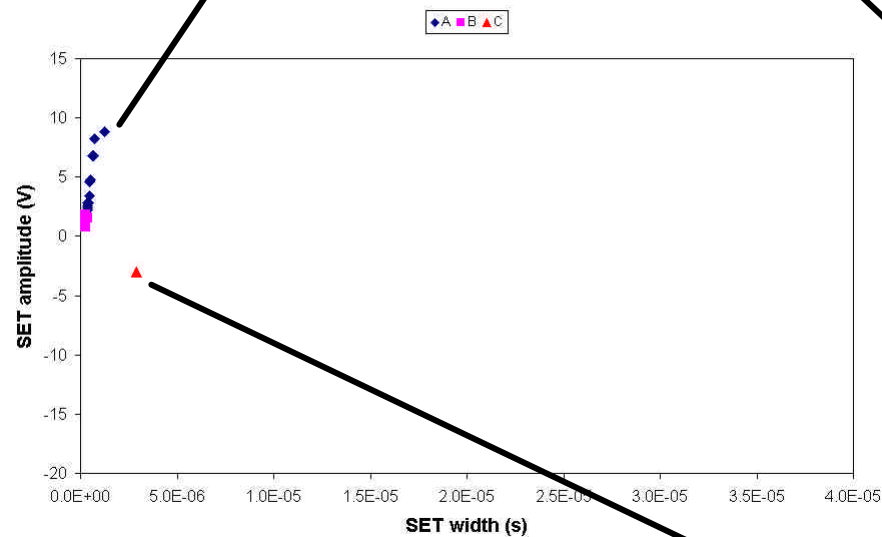
# Results – LM124



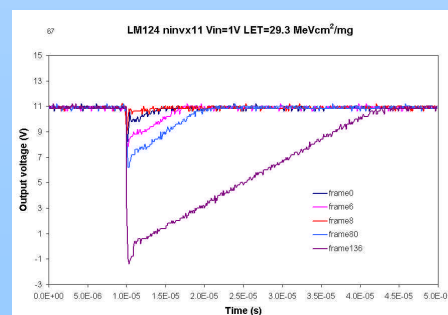
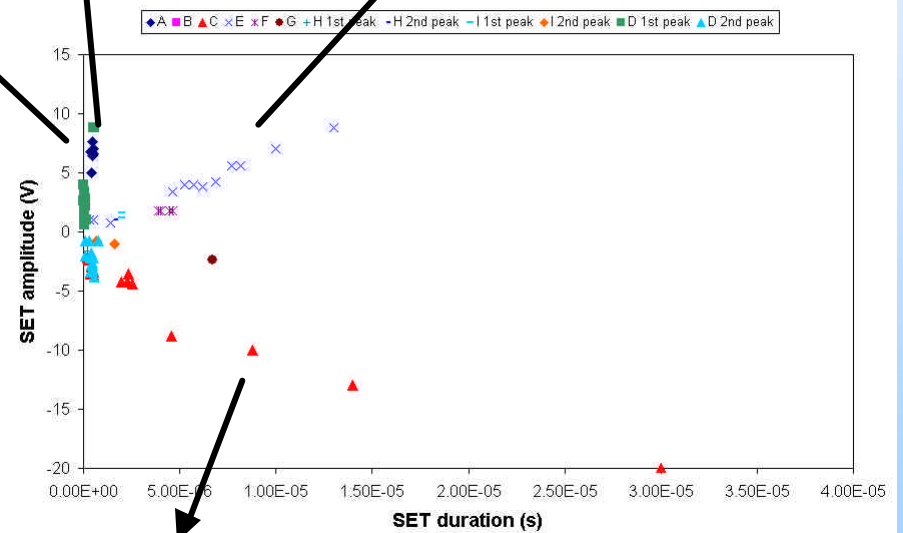
# Results – LM124



LM124 Voltage follower Vin=5V LET=2.8 MeVcm<sup>2</sup>/mg

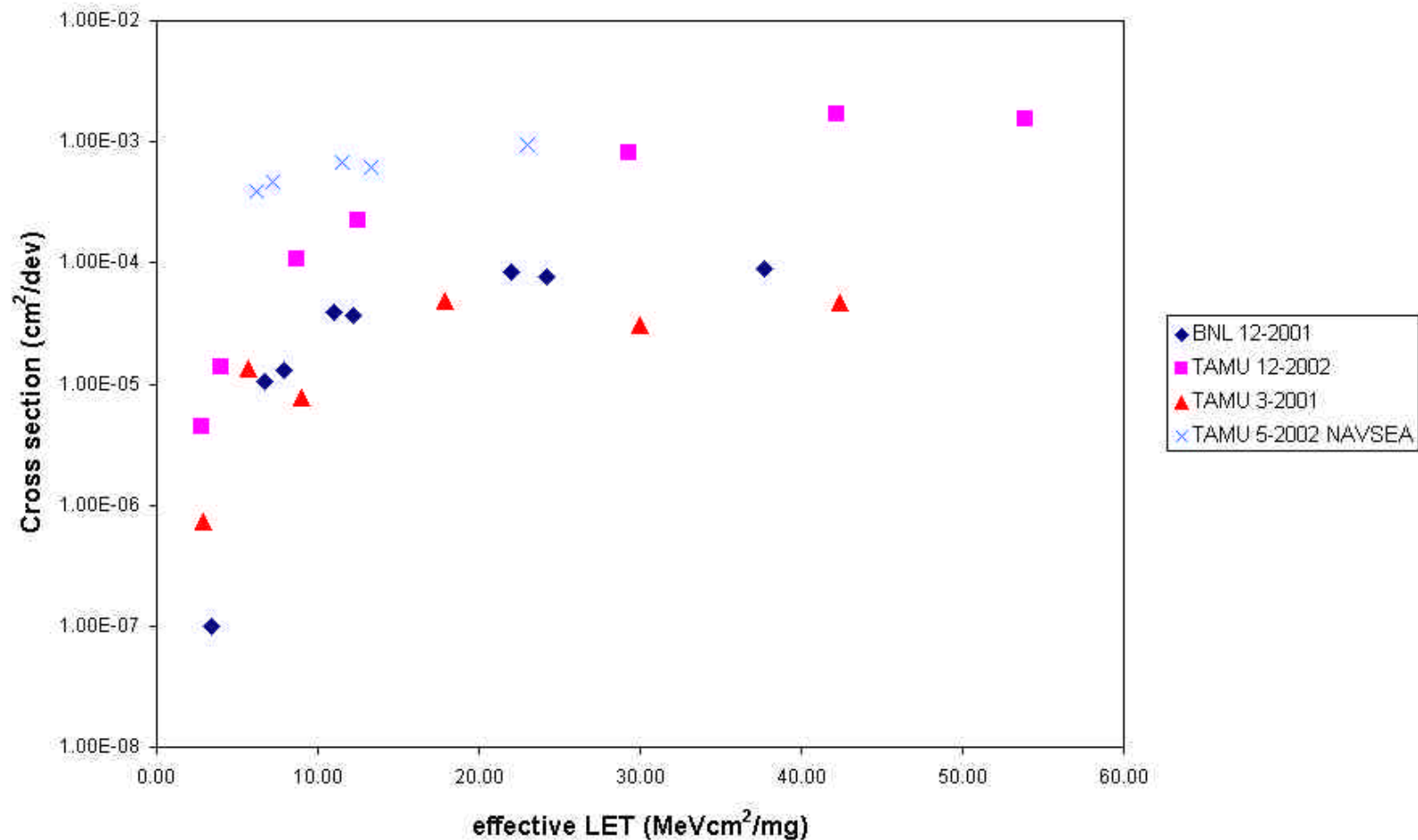


LM124 voltage follower Vin=5V LET=53.8 MeVcm<sup>2</sup>/mg

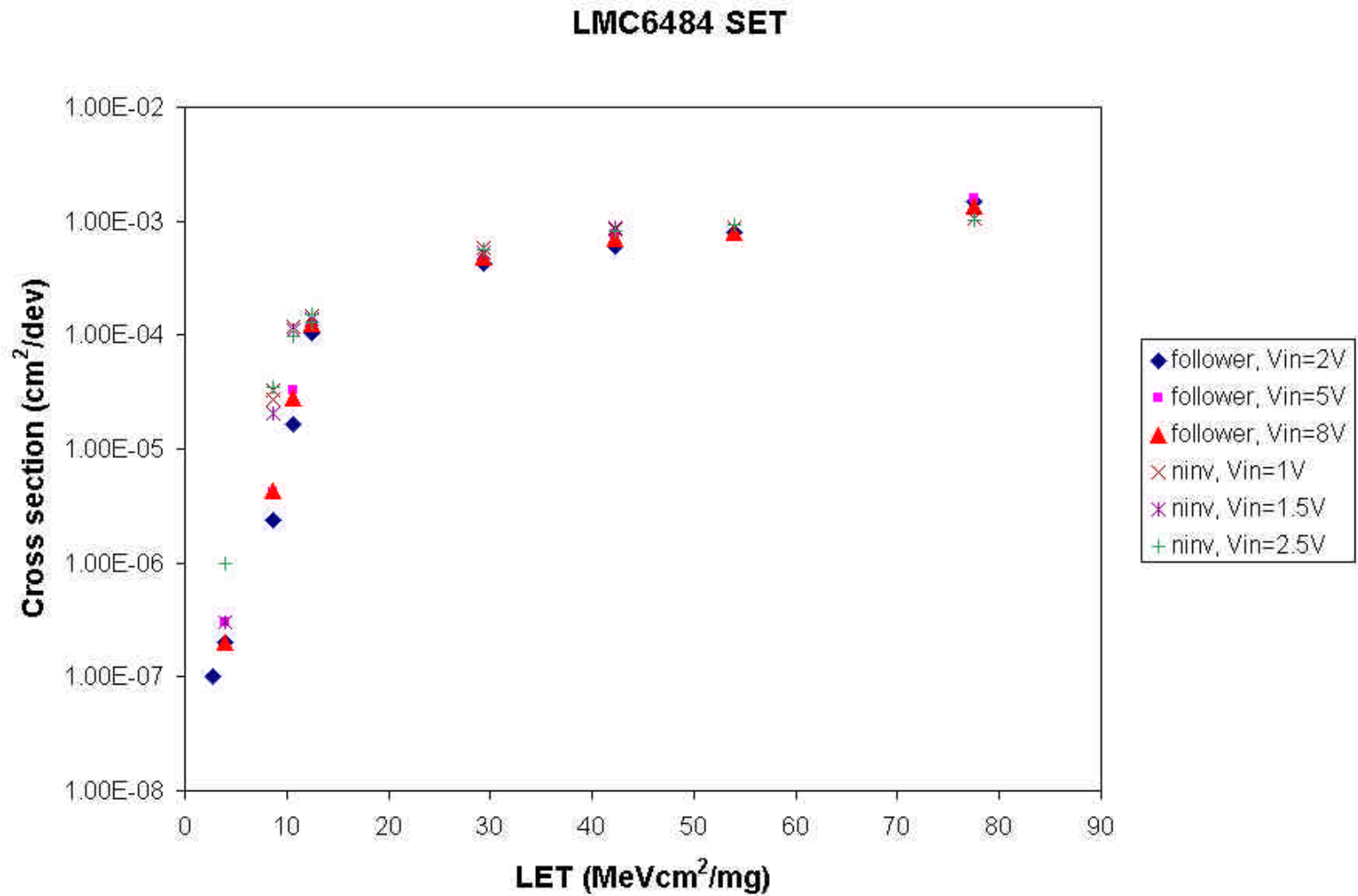


# Results – LM124

LM124 SET Voltage follower  $V_{in}=5V$

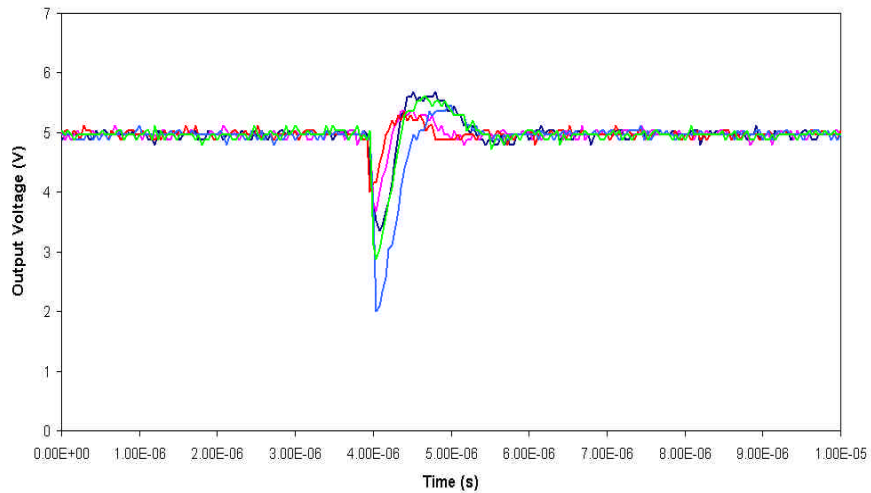


# Results – LMC 6484

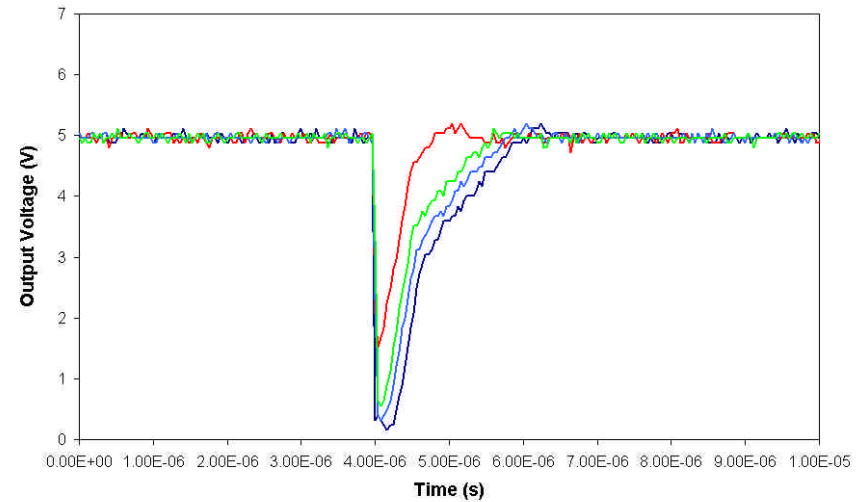


# Results – LMC 6484

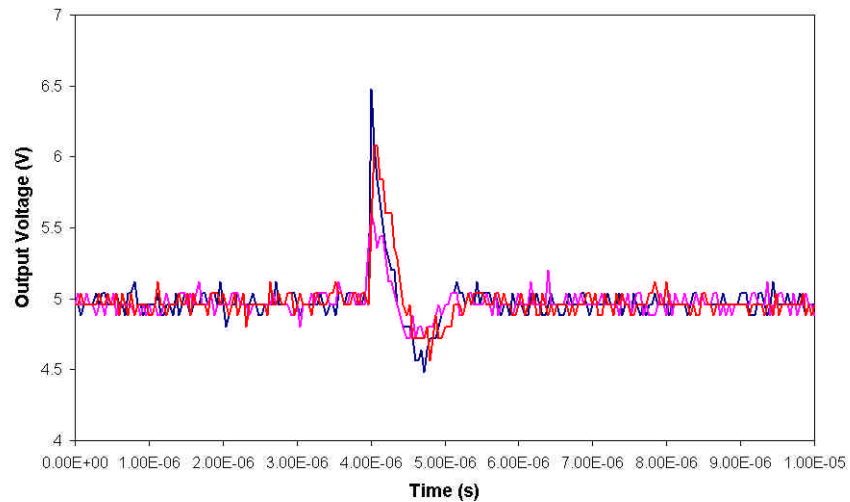
LMC6484 voltage follower  $V_{in}=5V$  LET=29.3 MeVcm<sup>2</sup>/mg



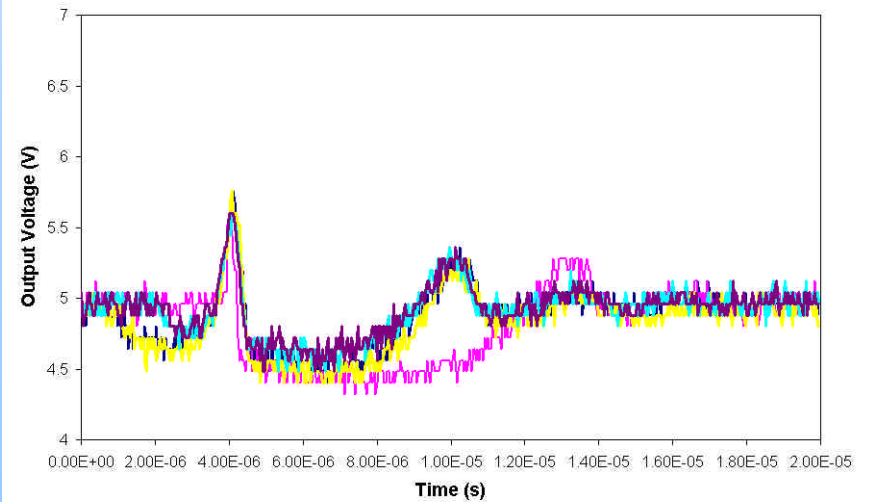
LMC6484 Voltage follower  $V_{in}=5V$  LET=29.3 MeVcm<sup>2</sup>/mg



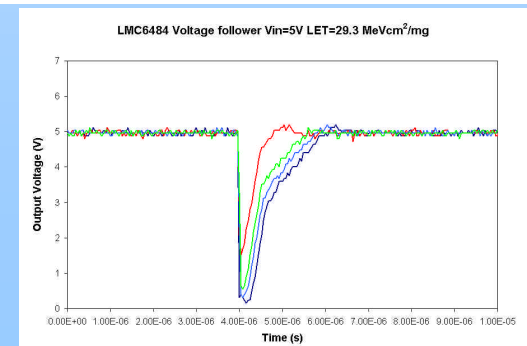
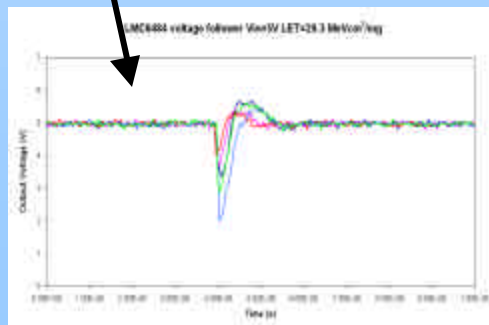
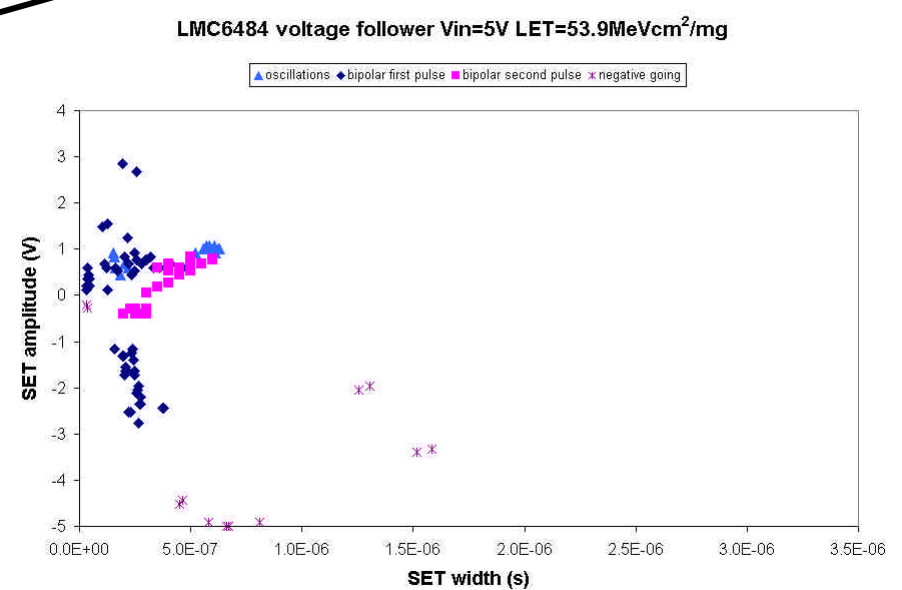
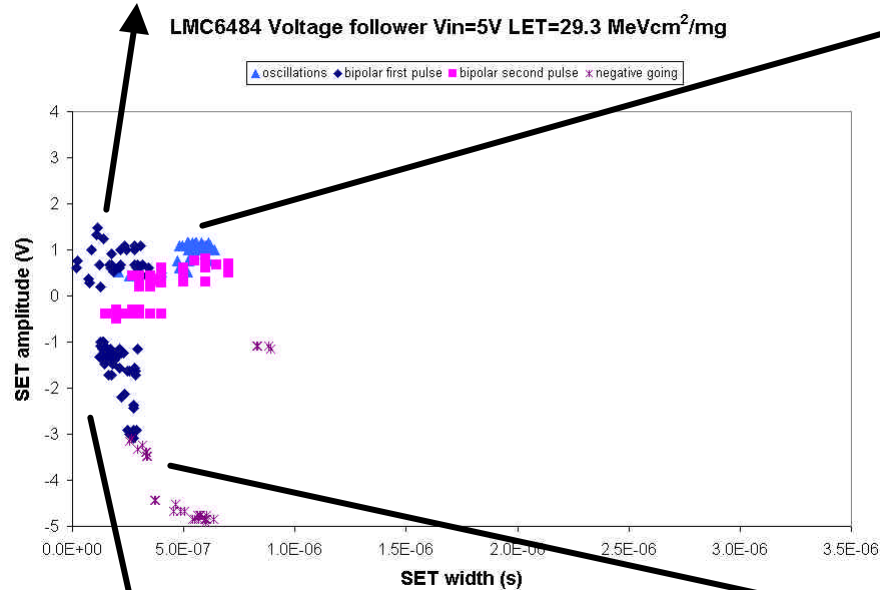
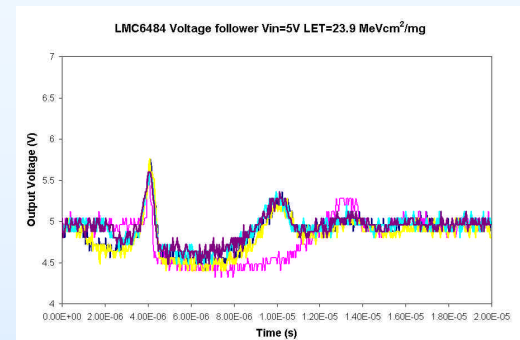
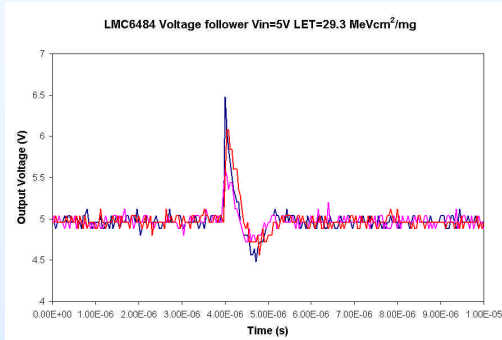
LMC6484 Voltage follower  $V_{in}=5V$  LET=29.3 MeVcm<sup>2</sup>/mg



LMC6484 Voltage follower  $V_{in}=5V$  LET=23.9 MeVcm<sup>2</sup>/mg

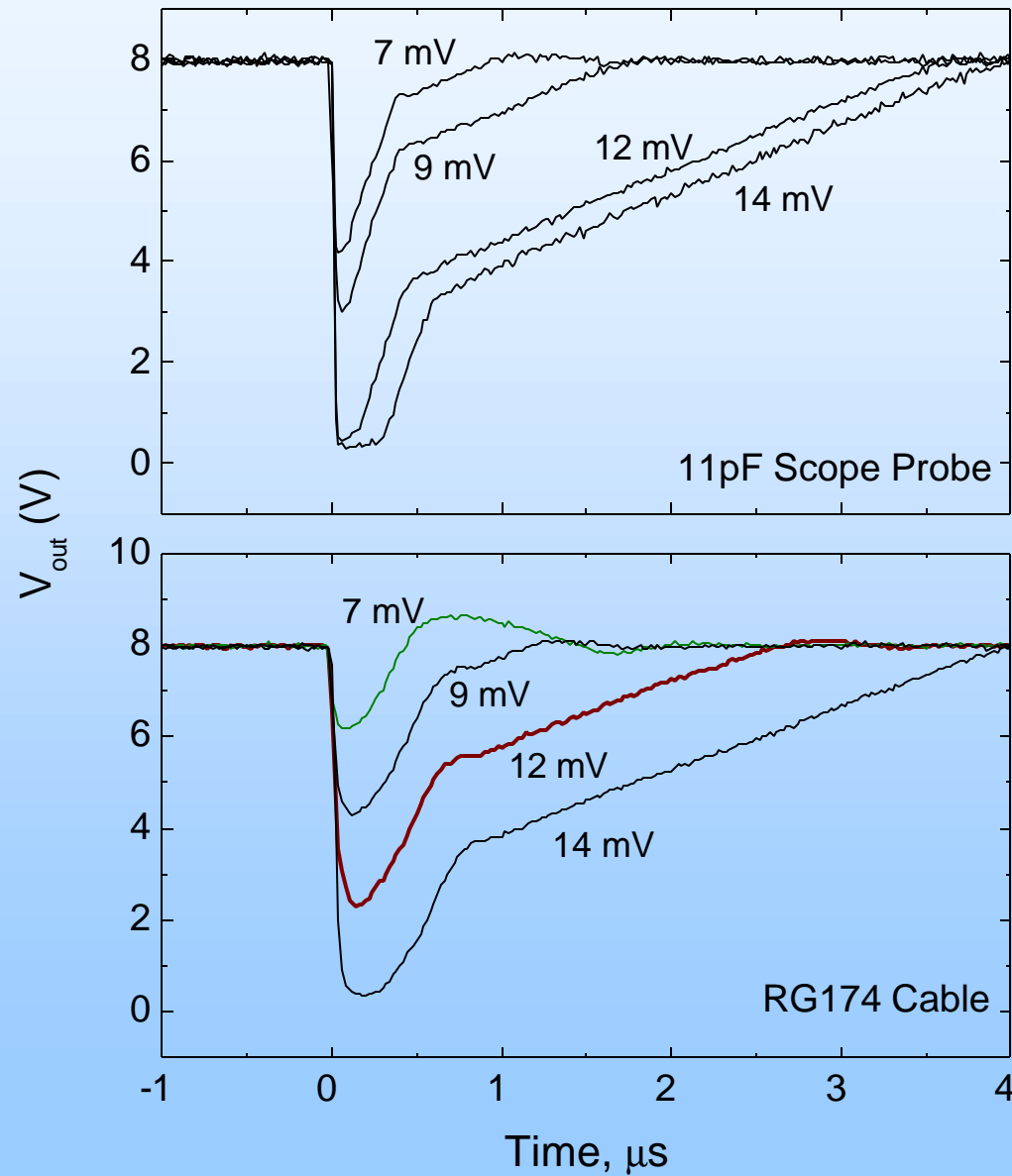


# Results – LMC 6484

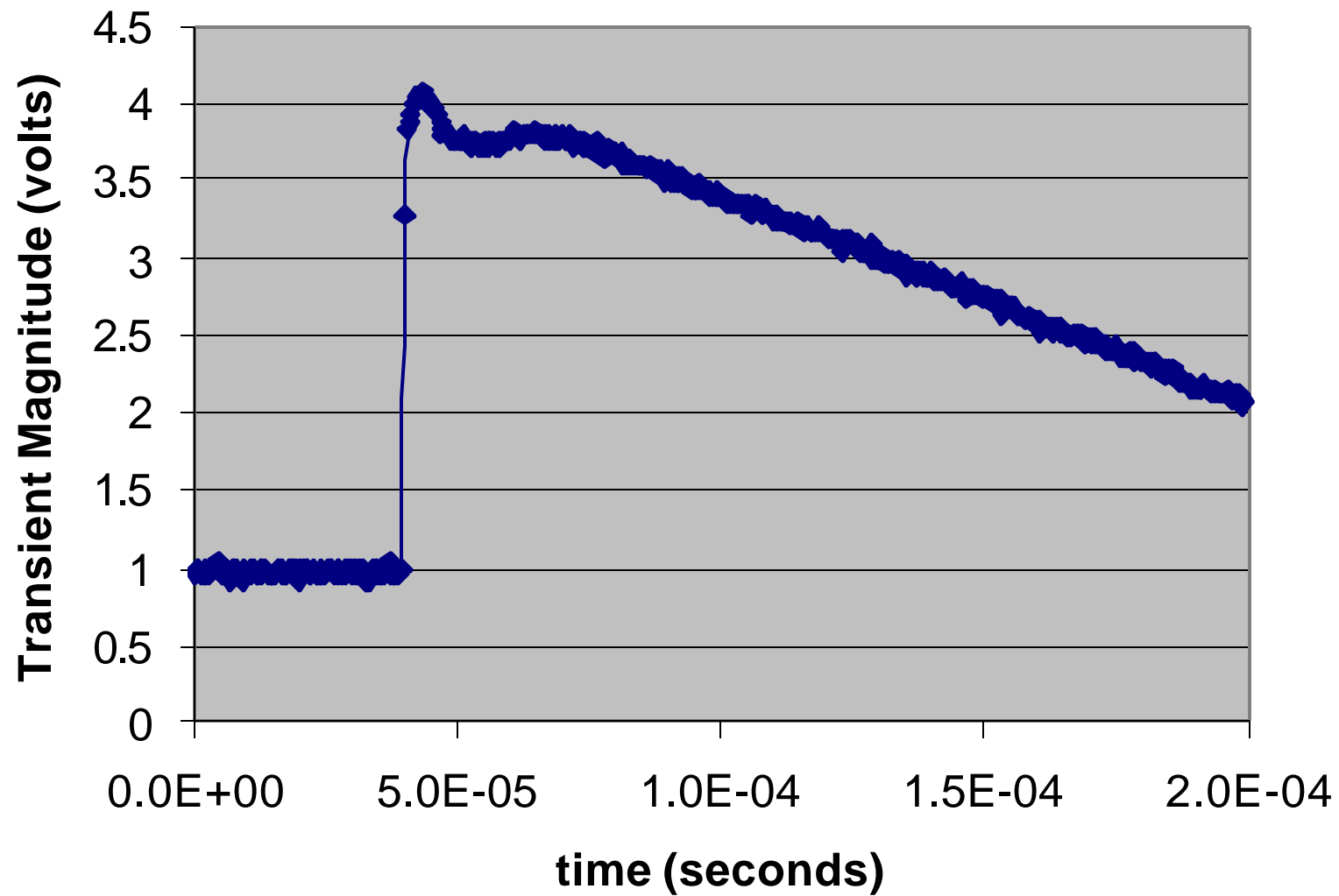


# Results – LMC 6484

LMC6484 Laser SET (590 nm)



## Results – OP293



# Lessons learned

- Different bias conditions and applications give different responses. It is often difficult to define the worst-case condition based on a limited set of bias conditions
  - Test in the application condition
  - Laser testing
  - Modeling
- SET characteristics are significantly affected by test set-up conditions and irradiation conditions. -> see testing guidelines
- A detailed data analysis is very important to assess the impact in applications.
- Flight experiments would be very useful

# Future work

- provide more accurate transient characteristics data to designers -> SET design book

